



PTO/SB/08A/B (09-06)

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Substitute for form 1449/PTO			Complete if Known		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)			Application Number	10/812,676-Conf. #3570	
			Filing Date	March 30, 2004	
			First Named Inventor	Martin W. Rupich	
			Art Unit	1722	
			Examiner Name	R. M. Kunemund	
Sheet	1	of	2	Attorney Docket Number	0002802.00169US1

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
/RK/	AA	US-08/943,047	10-01-1997	Thieme		
↓	AB	US-09/007,373	01-15-1998	Fritzemeier et al.		
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	AD*	US-2002/0056401-A1	05-16-2002	Rupich et al		
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	AF*	US-2002/0056401-A1	05-16-2002	Rupich et al.		
	AG*	US-2003/0130129-A1	07-10-2003	Seleznov et al		
	AH*	US-2005/0016759-A1	01-27-2005	Malozemoff et al.		
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↓	AV*	US-6,673,387	01-06-2004	Zhang et al		
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↓	AX*	US-6,745,059-A1	06-01-2004	Buczek et al		
↓	AY*	US-6,797,313	09-28-2004	Fritzemeier et al		
↓	AZ*	US-6,828,507	12-07-2004	Fritzemeier et al		
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Examiner Initials*	Cite No. ¹	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ³
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)					
/RK/	BA	WO-98/58415		12-23-1998	Massachusetts Institute of Technology		
/RK/	BB	WO-99/25908		05-27-1999	The Board of Trustees of the Leland Stanford Junior University		
/RK/	BC	WO-01/08236		02-01-2001	American Superconductor Corporation		

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Examiner Signature		Date Considered	
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NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²
/RK/	CA	EUROPEAN PATENT OFFICE, International Search Report of PCT/US2005/010593 mailed 14 November 2005, 3 pages			
/RK/	CB	PARANTHAMAN, M. et al, "Growth of Textured Buffer Layers and Superconductors on Rolled Ni Substrates Using Sol-gel Alkoxide Precursors", Ninth CIMTEC World Ceramics Congress and Forum on New Materials, Florence, Italy, 1998, pp. 185-192			
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/RK/	CF	SCHWARTZ, "Control of Microstructure and Orientation in Solution-Deposited BaTiO ₃ and Sr TiO ₃ Thin Films", J. Am. Ceram. Soc., 1999, Vol. 82, No. 9, pp. 2359-2367			
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature	/Robert Kunemund/	Date Considered	03/27/2007
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